

BULD116D

MEDIUM VOLTAGE FAST-SWITCHING NPN POWER TRANSISTOR

- INTEGRATED ANTIPARALLEL COLLECTOR- EMITTER DIODE
- LOW SPREAD OF DYNAMIC PARAMETERS
- MINIMUM LOT-TO-LOT SPREAD FOR RELIABLE OPERATION
- VERY HIGH SWITCHING SPEED
- THROUGH-HOLE IPAK (TO-251) POWER PACKAGE IN TUBE (SUFFIX "-1")

APPLICATIONS:

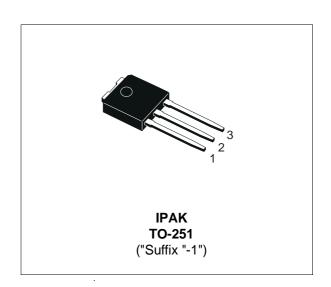
- COMPACT FLUORESCENT LAMPS UP TO 23 W AT 110 V A.C. MAINS
- FLYBACK AND FORWARD SINGLE TRANSISTOR LOW POWER CONVERTERS AT 110 V A.C. MAINS

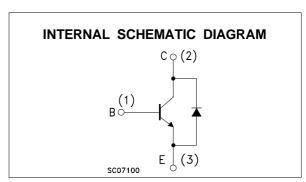


The device is manufactured using Multi Epitaxial Planar technology for high switching speeds and medium voltage capability.

It uses a Cellular Emitter structure with planar edge termination to enhance switching speeds while maintaining the wide RBSOA.

The device is designed for use in lighting applications and low cost switch-mode power supplies.





ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
Vces	Collector-Emitter Voltage (V _{BE} = 0)	400	V
V _{CEO}	Collector-Emitter Voltage (I _B = 0)	200	V
V _{EBO}	Emitter-Base Voltage (I _C = 0)	9	V
Ic	Collector Current	5	А
I _{CM}	Collector Peak Current (t _p < 5 ms) 10		А
Ι _Β	Base Current	2	А
I _{BM}	Base Peak Current (t _p < 5 ms)	4	А
P _{tot}	Total Dissipation at T _c = 25 °C	20	W
T _{stg}	Storage Temperature	-65 to 150	°C
Tj	Max. Operating Junction Temperature	150	°C

September 2003 1/6

THERMAL DATA

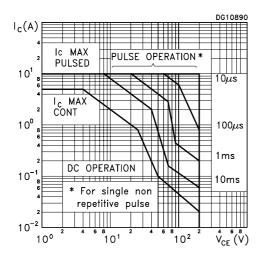
R _{thj-case}	Thermal Resistance Junction-Case	Max	6.25	°C/W
$R_{thj-amb}$	Thermal Resistance Junction-Ambient	Max	100	°C/W

ELECTRICAL CHARACTERISTICS (T_{case} = 25 °C unless otherwise specified)

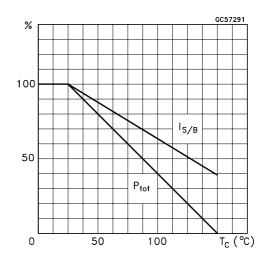
Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Unit
I _{CES}	Collector Cut-off Current (V _{BE} = 0)	V _{CE} = 400 V V _{CE} = 400 V	T _j = 125 °C			100 500	μA μA
V _{EBO}	Emitter-Base Voltage (I _C = 0)	I _E = 10 mA		9			V
V _{CEO(sus)*}	Collector-Emitter Sustaining Voltage (I _B = 0)	I _C = 100 mA	L = 25 mH	200			V
I _{CEO}	Collector-Emitter Leakage Current	V _{CE} = 200 V				250	μΑ
VCE(sat)*	Collector-Emitter Saturation Voltage	I _C = 0.5 A I _C = 1 A I _C = 3 A I _C = 5 A	$I_B = 50 \text{ mA}$ $I_B = 0.1 \text{ A}$ $I_B = 0.6 \text{ A}$ $I_B = 1 \text{ A}$			0.25 0.4 0.7 1.2	V V V
V _{BE(sat)} *	Base-Emitter Saturation Voltage	I _C = 1 A I _C = 5 A	I _B = 0.1 A I _B = 1 A			1.1 1.5	V V
h _{FE} *	DC Current Gain	I _C = 10 mA I _C = 5 A	V _{CE} = 5 V V _{CE} = 5 V	10 8		20	
t _r t _f t _s	RESISTIVE LOAD Rise Time Fall Time Storage Time	$V_{CC} = 125 \text{ V}$ $I_{B1} = 0.4 \text{ A}$ $t_p = 30 \mu\text{s}$	$I_C = 2 A$ $I_{B2} = -0.4 A$ (see figure 2)		0.2 0.2 1.4	0.4	μs μs μs
t _s t _f	INDUCTIVE LOAD Storage Time Fall Time	I _C = 2 A V _{BE} = -5 V V _{clamp} = 180 V	$I_{B1} = 0.4 A$ $L = 500 \mu H$ (see figure 1)		0.5 0.10		μs μs
V_{F}	Diode Forward Voltage	I _C = 2 A				1.5	V

^{*} Pulsed: Pulse duration = 300 μs, duty cycle 1.5 %

Safe Operating Area

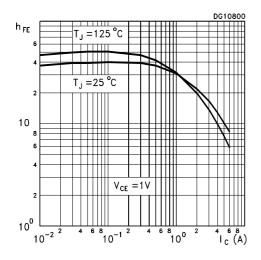


Derating Curve

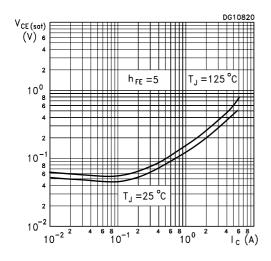


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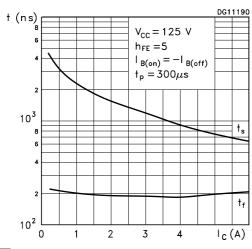
DC Current Gain



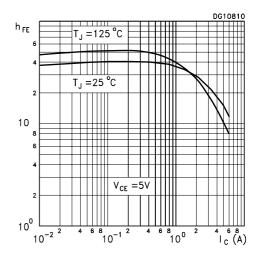
Collector-Emitter Saturation Voltage



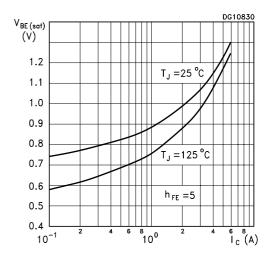
Switching Time Resistive Load



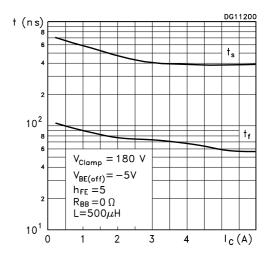
DC Current Gain



Base-Emitter Saturation Voltage



Switching Time Inductive Load



Reverse Biased SOA

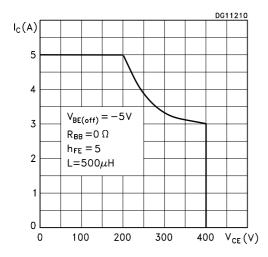


Figure 1: Inductive Load Switching Test Circuit.

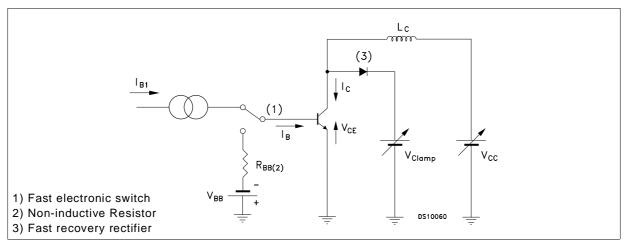
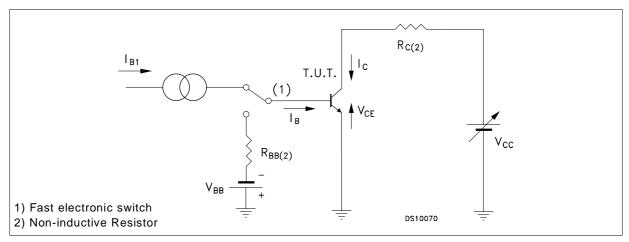


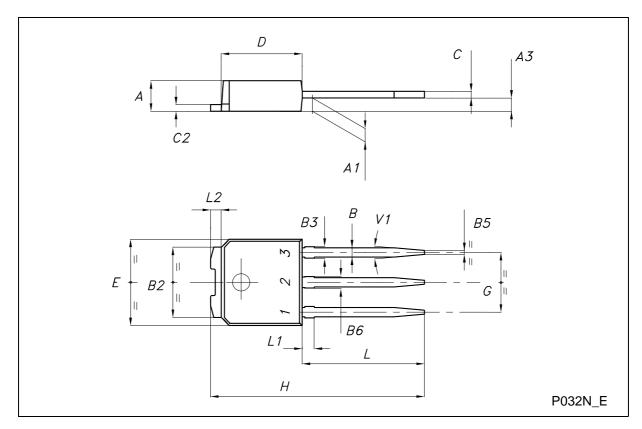
Figure 2: Resistive Load Switching Test Circuit.



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TO-251 (IPAK) MECHANICAL DATA

DIM.		mm			inch	
DIIVI.	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
Α	2.20		2.40	0.087		0.094
A1	0.90		1.10	0.035		0.043
A3	0.70		1.30	0.028		0.051
В	0.64		0.90	0.025		0.035
B2	5.20		5.40	0.204		0.213
В3			0.85			0.033
B5		0.30			0.012	
В6			0.95			0.037
С	0.45		0.60	0.018		0.024
C2	0.48		0.60	0.019		0.024
D	6.00		6.20	0.237		0.244
Е	6.40		6.60	0.252		0.260
G	4.40		4.60	0.173		0.181
Н	15.90		16.30	0.626		0.642
L	9.00		9.40	0.354		0.370
L1	0.80		1.20	0.031		0.047
L2		0.80	1.00		0.031	0.039
V1		10°			10°	



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